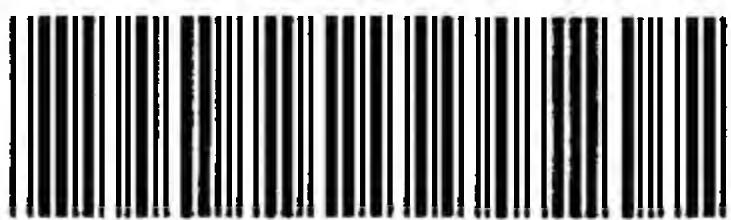


Search Notes



Application/Control No.

10/708.175

Examiner

Jack Chen

**Applicant(s)/Patent under
Reexamination**

YEH, WEN-YUAN

Art Unit

2813

SEARCHED

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)